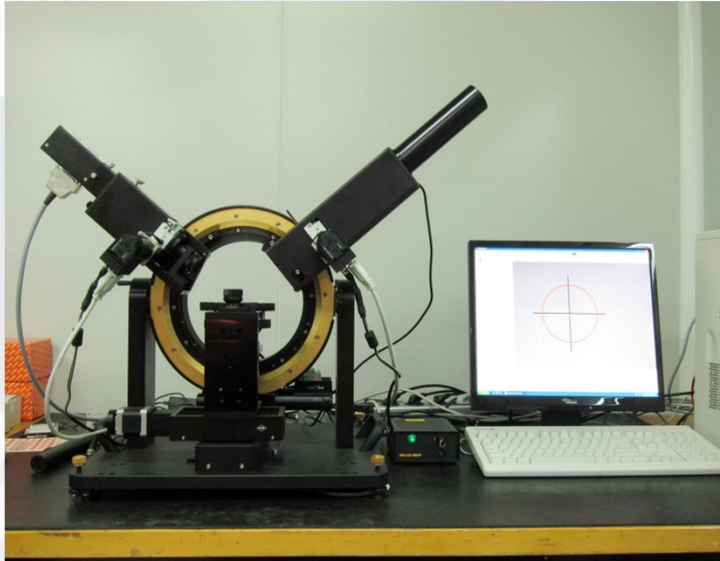


# 椭圆偏振仪



## ➤参数指标:

Wavelength: 632.8nm

Incidence range:  $20^{\circ} - 150^{\circ}$

Angle resolution:  $0.005^{\circ}$

Accuracy: 0.1nm

Lateral resolution (imaging Ellipsometry):  $1 \mu\text{m}$

椭圆偏振仪(Multiskop)是一台多功能表面测量仪，集椭圆偏振仪，表面等离子体共振光谱分析，光波导模式，布鲁斯特角显微镜，成像椭圆偏振仪等多种功能于一体，主要用于测量固体膜，液体膜的厚度，材料的光学参数，以及研究薄膜动力学过程等。

The Multiskop is a powerful and versatile optical setup which incorporates modules such as Ellipsometry, Surface Plasmon Spectroscopy, Waveguide modes, Brewster Angle Microscopy and Imaging Ellipsometry in a single instrument. It is can be used to measure the thickness of solid/ liquid film, optical constant of material and the kinetic process, and so on.